1762

**DOCKET NO.: CFMT-0255** 

**PATENT** 



## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In Re Application of:

Steven Verhaverbeke

Serial No.: 10/074,516

**Group Art Unit: 1762** 

Filing Date: February 13, 2002

**Examiner: Not Yet Assigned** 

For: METHOD FOR ETCHING ELECTRONIC COMPONENTS CONTAINING

TANTALUM

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DATE OF DEPOSIT: 5/03/02

I HEREBY CERTIFY THAT THIS PAPER IS BEING DEPOSITED WITH THE UNITED STATES POSTAL SERVICE AS FIRST CLASS MAIL, POSTAGE PREPAID ON THE DATE INDICATED ABOVE AND IS ADDRESSED TO THE ASSISTANT COMMISSIONER FOR PATENTS,

WASHINGTON) DC 20231

TYPED NAME: David R. Bailey REGISTRATION NO.:35,057

Assistant Commissioner for Patents Washington, D.C. 20231

Dear Sir:

## INFORMATION DISCLOSURE STATEMENT

Pursuant to 37 C.F.R. §1.56 and in accordance with 37 C.F.R. §§1.97-1.98, information relating to the above-identified application is hereby disclosed. Inclusion of information in this statement is not to be construed as an admission that this information is material as that term is defined in 37 C.F.R. §1.56(b).

In accordance with §1.97(b), since this Information Disclosure Statement is being filed either within three months of the filing date of the above-identified application, within three months of the date of entry into the national stage of the above identified application as set forth in §1.491, before the mailing date of a first Office Action on the merits of the above-identified application, or before the mailing date of a first office action after the filing of request for continued examination under §1.114, no additional fee is required.

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	In accordance	e with §1.129(a	), this Information [	Disclosure Sta	tement is being
	filed in con	nection with	the first or $\square_{\text{seco}}$	ond After Fin	nal Submission,
	therefore:				
	□ Certi	fication in Accor	dance with §1.97(e)	is attached; o	r
	☐ The	Gee of <b>\$180.00</b> as	set forth in §1.17(p	) is attached.	
	In accordance	e with §1.97(c),	his Information Disc	closure Statem	ent is being filed
	after the per	iod set forth in §	1.97(b) above but be	fore the maili	ng date of either
	a Final Actio	on under §1.113 (	or a Notice of Allowa	ance under §1.	311, or before an
	action that c	therwise closes	prosecution in the ap	plication, ther	refore:
		Certification	in Accordance with	§1.97(e) is atta	ached; or
		The fee of <u>\$1</u>	80.00 as set forth in	§1.17(p) is att	tached.
	In accordan	ce with §1.97(d),	this Information Dis	closure Staten	nent is being filed
	after the m	ailing date of e	ther a Final Action	under §1.11.	3 or a Notice of
			before, or simultane		
	Issue Fee, th	nerefore included	l are: Certification in	Accordance w	vith §1.97(e); and
	the submiss	ion fee of \$180.	00 as set forth in §1.	17(p).	
$\boxtimes$	Copies of	each of the refe	rences listed on the	attached For	m PTO-1449 are
	enclosed he	erewith.			
	Copies of r	eferences listed o	n the attached Form F	PTO-1449 are	enclosed herewith
	EXCEPT 7	THAT:			
	□ In v	view of the volun	ninous nature of refer	ences [list as a	appropriate], and
	the	likelihood that t	hese references are a	vailable to the	Examiner, copies
	are	not enclosed he	rewith.		

**DOCKET NO.: CFMT-0255** 

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**PATENT** 

- In accordance with §1.98(d), copies of the following references listed on the attached Form PTO-1449 are not enclosed herewith because they were previously cited by or submitted to the U.S. Patent and Trademark Office in patent application(s) for which a claim for priority under 35 U.S.C.§120 have been made in the instant application:
- Copies of references [list as appropriate] listed on the attached Form

  PTO-1449 were previously cited by or submitted to the Patent and

  Trademark Office in prior application Serial No. , filed .
  - ☐ If any of the foregoing publications are not available to the Examiner, Applicant will endeavor to supply copies at the Examiner's request.

Please charge any deficiency or credit any overpayment to Deposit Account No. 23-3050. This form is submitted in duplicate.

There are no listed references which are not in the English language.

Date: 5/3/02

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Registration No. 35,057

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	form ]	PTO-1449 Modifi	Docket No. CFMT-0255	Serial No. 10/074,516			
· (	C	Patent and Publication Cited by Applicant weral sheets if necessary		Applicant Steven Verhaverbeke			
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